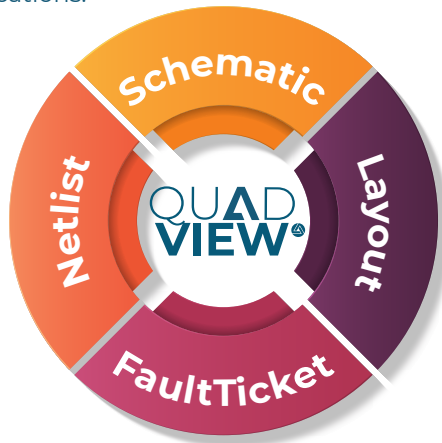


QUAD VIEW®

**Next Generation Viewers
for the Electronics
Industry**

QuadView® is a powerful set of scalable board viewing modules that can be used either as a standalone viewer or fully integrated within customer's applications.



SCHEMATIC VIEWER

QuadView has a unique digitization capability that allows users to create the schematic view directly from a searchable PDF file. Schematic views can also be created from other standard formats such as HPGL and Windows Metafile etc.

NETLIST NAVIGATOR

The innovative "Netlist Navigator" provides a virtual schematic view reconstructed directly from a netlist, which allows users to navigate easily through complex schematic hierarchies.

It also provides a unique capability to visualize component pin functionality, using advanced graphical symbols.

QuadView® can be used in the design environment to assist in DfT and test coverage analysis, at the schematic capture stage and during prototype debug. Within the manufacturing environment, it becomes an integral part of the repair cycle, assisting in the locating of faults and reducing repair time significantly

LAYOUT VIEWER

Layout views can be created from a number of industry formats such as GENCAD, CAMCAD, FATF, ODB++, or directly from any native CAD layout data such as Cadence, Mentor, Zuken, etc.

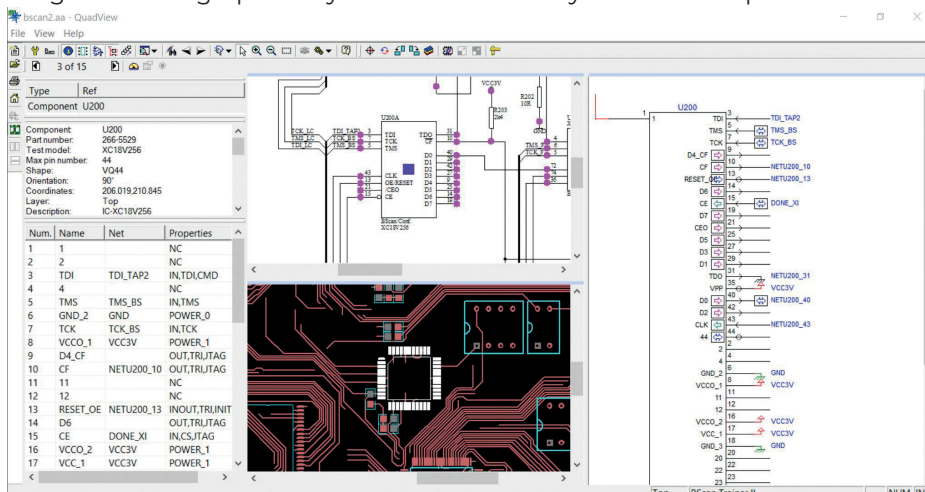
The layout view can be flipped or rotated to visualize either the top or bottom side views, to enable direct correlation with the board under test.

FAULT TICKET ANALYZER

The hot-link feature provides full interaction between component and net references, that appear as highlighted links within any type of paperless repair fault ticket, exported from test or inspection systems. This allows repair operators to quickly and easily find the location of faults, displayed in both the schematic and layout views. The fault ticket analyzer also simplifies test fixture debug and maintenance by displaying detailed tester channel and nail information that is necessary to carry out fixture repair.

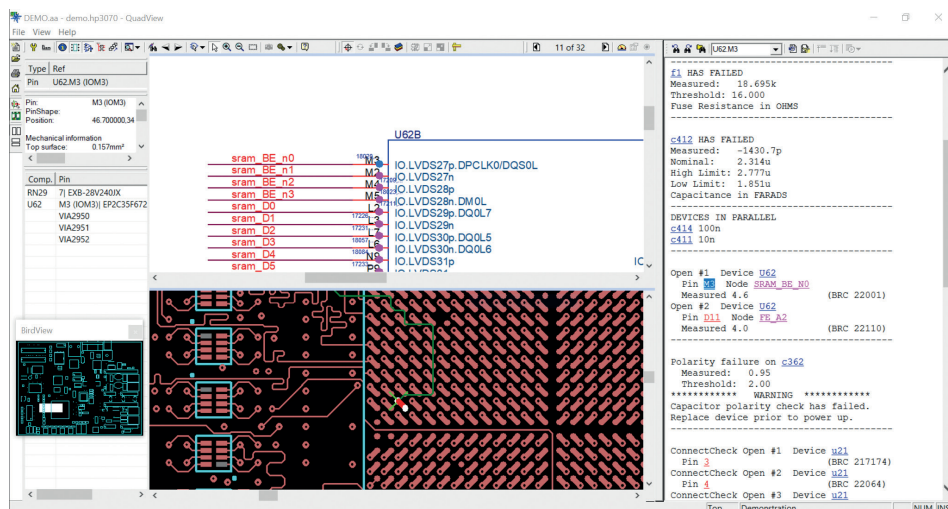
Key product benefits

- **Ease of Use**
Powerful, scalable visualization environment, consisting of schematic, netlist, layout and fault ticket viewing modules that can be used either standalone or integrated within customer's applications. No pre-processing of CAD data needed.
- **Schematic**
Unique digitization capability that creates a schematic view directly from a searchable PDF file which is fully interactive with layout and Netlist Navigator.
- **Netlist Navigator**
Reconstruct "virtual schematics" directly from a netlist, to provide a visual netlist navigation capability that includes advanced nodal detail.
- **Layout from native CAD formats**
Create layout views from standard CAD formats such as GENCAD, CAMCAD, FATF, ODB++, or direct from native CAD layout data.
- **Fault ticket hot-links**
Navigate between component and net references, that appear as highlighted hot-links, within the paperless fault ticket.
- **Fully Interactive Cross-probing**
Cross-probe between layout, schematic and netlist viewers, and other products within the ASTER portfolio such as TestWay™ and QUAD®.
- **Flexible color assignment**
Visualize test coverage and component pin properties, using the QuadView color assignment palette, to simplify analysis and fault class recognition.
- **Functional test editor**
Declare functional test coverage on both component and pin level. Simplify functional test diagnosis with the "Sherlock" algorithm.
- **Short-circuit search assistant**
Reduce the time to locate short-circuits by intelligently highlighting areas where solder bridges are most likely.



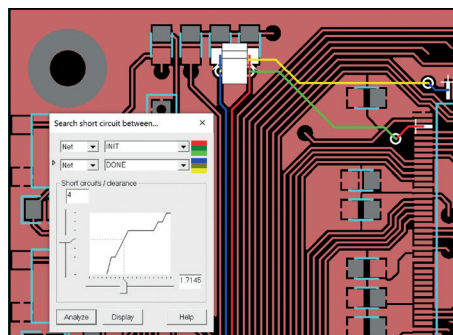
INTERACTIVE FAULT LOCATOR

QuadView® is fully customizable, it can be configured as a simple “component locator” or it can be part of a comprehensive failure tracking system, using bar code readers, networks and databases, so that failure data for an entire factory can be aggregated, analyzed and acted upon in real time.



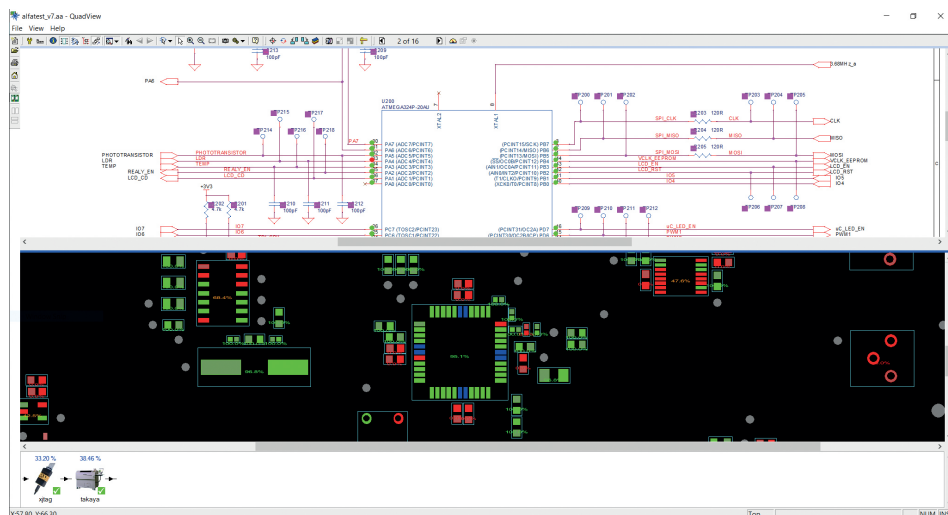
SHORT CIRCUIT SEARCH ASSISTANT

This unique feature reduces the time to locate short-circuits, by intelligently highlighting areas within the layout view where solder bridges are most likely to occur.



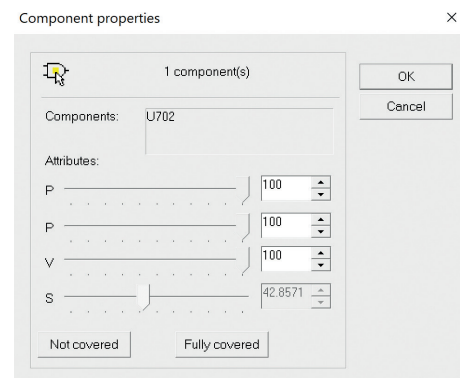
COVERAGE VISUALIZATION

QuadView® provides visualization of test coverage and pin level fault diagnosis, in both schematic and board layout views. The flexible color assignment palette allows users to customize component, pin and net viewing attributes, in order to simplify DfT and test coverage analysis and fault class recognition.

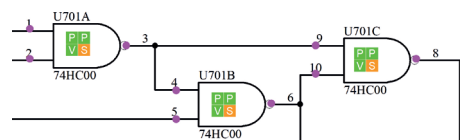


FUNCTIONAL TEST DECLARATION

QuadView® also includes the capability to declare predicted pin and component functional test coverage, based on the PPVS coverage model by selecting component clusters within the schematic view.



By selecting the “Edit coverage” utility within **QuadView®**, the user can zoom-in on a specific area within the schematic view and select a group of components that can be tested as a functional cluster. The test cluster is saved, along with the respective PPVS test coverage, as a user-definable test step within the coverage editor. This information can then be taken into account during any TestWay™ test coverage analysis.



The functional test feature also includes the “Sherlock” algorithm. This simplifies functional test diagnosis by predicting the most probable location of a faulty component, based on the analysis of previously obtained test results, that identify already tested paths.

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